TOSHIBA

TOSHIBA TRANSISTOR SILICON NPN EPITAXIAL TYPE (PCT PROCESS)

2 S C 4 4 0 8

POWER AMPLIFIER APPLICATIONS

POWER SWITCHING APPLICATIONS

• Low Collector Saturation Voltage: VCE (sat) = 0.5V (Max.)

• High Collector Power Dissipation : PC=900mW (Ta=25°C)

• High Speed Switching Time : t_{Stg}=500ns (Typ.)

• Complementary to 2SA1680

MAXIMUM RATINGS (Ta = 25°C)

CHARACTERISTIC	SYMBOL	RATING	UNIT
Collector-Base Voltage	v_{CBO}	80	V
Collector-Emitter Voltage	v_{CEO}	50	V
Emitter-Base Voltage	$V_{ m EBO}$	6	V
Collector Current	$I_{\mathbf{C}}$	2	A
Base Current	$I_{\mathbf{B}}$	0.2	Α
Collector Power Dissipation	$P_{\mathbf{C}}$	900	mW
Junction Temperature	T_j	150	°C
Storage Temperature Range	$T_{ m stg}$	-55~150	°C

Unit in mm 5.1MAX. 0.75MAX. 1.0MAX. 0.8MAX. 0.6MAX. 1. EMITTER 2. COLLECTOR 3. BASE JEDEC TO-92MOD EIAJ —

2-5J1A

Weight: 0.36g (Typ.)

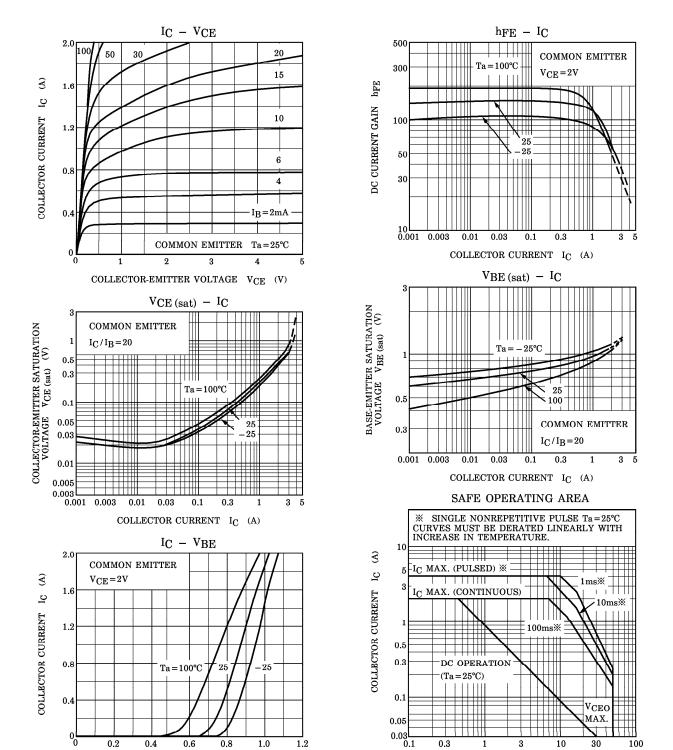
TOSHIBA

ELECTRICAL CHARACTERISTICS (Ta = 25°C)

ELECTRICAL CHARACTERISTICS (Ta = 25 C)					gnt : 0.00g (13p.)			
CHARAC	CTERISTIC	SYMBOL	TEST CONDITION	MIN.	TYP.	MAX.	UNIT	
Collector Cut-	off Current	I _{CBO}	$V_{CB} = 80V, I_{E} = 0$	<u> </u>	_	1.0	μA	
Emitter Cut-off Current		I _{EBO}	$V_{EB}=6V, I_{C}=0$	_	_	1.0	μ A	
Collector-Emit Voltage	tter Breakdown	V _(BR) CEO	$I_{C}=10mA, I_{B}=0$	50	_	_	v	
DC Current Gain		hFE (1)	$V_{CE} = 2V, I_{C} = 100 \text{mA}$	120	_	400		
		h _{FE} (2)	$V_{CE} = 2V, I_{C} = 1.5A$	40	_	_]	
Collector-Emit Voltage	tter Saturation	V _{CE} (sat)	$I_{C}=1A, I_{B}=0.05A$	_	_	0.5	V	
Base-Emitter Voltage	Saturation	V _{BE} (sat)	$I_{C}=1A, I_{B}=0.05A$	_	_	1.2	V	
Transition Frequency		${ m f_T}$	$V_{CE}=2V, I_{C}=100mA$	_	100	_	MHz	
Collector Output Capacitance		C_{ob}	$V_{CB} = 10V, I_E = 0, f = 1MHz$	_	14	_	pF	
Switching Time	Turn-on Time	t _{on}	20μs OUTPUT IB1 INPUT	_	0.1	_		
	Storage Time	t_{stg}	I_{B2} I_{B2} m	_	0.5	_	μ s	
	Fall Time	t_f	$\begin{vmatrix} I_{B1} = -I_{B2} = 0.05A, & \checkmark & \circ \\ DUTY \ CYCLE \le 1\% & V_{CC} = 30V \end{vmatrix}$	_	0.1	_		

961001EAA2

[●] TOSHIBA is continually working to improve the quality and the reliability of its products. Nevertheless, semiconductor devices in general can malfunction or fail due to their inherent electrical sensitivity and vulnerability to physical stress. It is the responsibility of the buyer, when utilizing TOSHIBA products, to observe standards of safety, and to avoid situations in which a malfunction or failure of a TOSHIBA product could cause loss of human life, bodily injury or damage to property. In developing your designs, please ensure that TOSHIBA products are used within specified operating ranges as set forth in the most recent products specifications. Also, please keep in mind the precautions and conditions set forth in the TOSHIBA Semiconductor Reliability Handbook.



100

The information contained herein is presented only as a guide for the applications of our products. No responsibility is assumed by TOSHIBA CORPORATION for any infringements of intellectual property or other rights of the third parties which may result from its use. No license is granted by implication or otherwise under any intellectual property or other rights of TOSHIBA CORPORATION or others. The information contained herein is subject to change without notice.

1.2

 $BASE\text{-}EMITTER\ VOLTAGE\quad V_{BE}\quad (V)$

COLLECTOR-EMITTER VOLTAGE VCE (V)